



**SEMiX® 5**

## Trench IGBT Modules

### SEMiX305GD07E4

#### Features\*

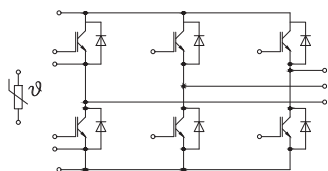
- Solderless assembly solution with PressFIT signal pins and screw power terminals
- IGBT 4 Trench Gate Technology
- $V_{CE(sat)}$  with positive temperature coefficient
- Low inductance case
- Reliable mechanical design with injection moulded terminals and robust internal connections
- UL recognized file no. E63532
- NTC temperature sensor inside

#### Typical Applications

- Three phase inverters for AC motor speed control
- UPS

#### Remarks

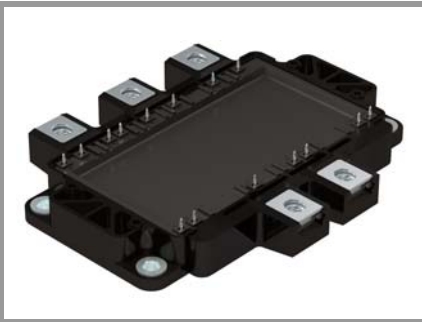
- Case temperature limited to  $T_C=125^\circ\text{C}$  max.
- Product reliability results are valid for  $T_{jop}=150^\circ\text{C}$
- Dynamic data are estimated
- For storage and case temperature with TIM see document "TP(HALA P8) SEMiX 5p"



GD

Absolute Maximum Ratings			
Symbol	Conditions	Values	Unit
<b>IGBT</b>			
$V_{CES}$	$T_j = 25^\circ\text{C}$	650	V
$I_C$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	372
		$T_c = 80^\circ\text{C}$	281
$I_{Cnom}$		300	A
$I_{CRM}$		900	A
$V_{GES}$		-20 ... 20	V
$t_{psc}$	$V_{CC} = 360\text{ V}$ $V_{GE} \leq 15\text{ V}$ $V_{CES} \leq 650\text{ V}$	$T_j = 150^\circ\text{C}$	10
$T_j$		-40 ... 175	$^\circ\text{C}$
<b>Inverse diode</b>			
$V_{RRM}$	$T_j = 25^\circ\text{C}$	650	V
$I_F$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	335
		$T_c = 80^\circ\text{C}$	244
$I_{FRM}$		600	A
$I_{FSM}$	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$	2160	A
$T_j$		-40 ... 175	$^\circ\text{C}$
<b>Module</b>			
$I_{t(RMS)}$		400	A
$T_{stg}$	module without TIM	-40 ... 125	$^\circ\text{C}$
$V_{isol}$	AC sinus 50Hz, $t = 1\text{ min}$	4000	V

Characteristics					
Symbol	Conditions	min.	typ.	max.	Unit
<b>IGBT</b>					
$V_{CE(sat)}$	$I_C = 300\text{ A}$ $V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.55	1.95	V
		$T_j = 150^\circ\text{C}$	1.75		V
$V_{CE0}$	chipelevel	$T_j = 25^\circ\text{C}$	0.90	1.00	V
		$T_j = 150^\circ\text{C}$	0.82		V
$r_{CE}$	$V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	2.2	3.2	$\text{m}\Omega$
		$T_j = 150^\circ\text{C}$	3.1		$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 8\text{ mA}$	5.1	5.8	6.4	V
$I_{CES}$	$V_{GE} = 0\text{ V}, V_{CE} = 650\text{ V}, T_j = 25^\circ\text{C}$			0.2	$\text{mA}$
$C_{ies}$	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	18.5		$\text{nF}$
$C_{oes}$		$f = 1\text{ MHz}$	1.16		$\text{nF}$
$C_{res}$		$f = 1\text{ MHz}$	0.55		$\text{nF}$
$Q_G$	$V_{GE} = -15\text{ V} \dots +15\text{ V}$		3023		$\text{nC}$
$R_{Gint}$	$T_j = 25^\circ\text{C}$		1.0		$\Omega$
$t_{d(on)}$	$V_{CC} = 300\text{ V}$ $I_C = 300\text{ A}$	$T_j = 150^\circ\text{C}$	55		ns
$t_r$	$V_{GE} = +15/-15\text{ V}$	$T_j = 150^\circ\text{C}$	67		ns
$E_{on}$	$R_{G on} = 2\ \Omega$	$T_j = 150^\circ\text{C}$	5.4		mJ
$t_{d(off)}$	$R_{G off} = 2\ \Omega$	$T_j = 150^\circ\text{C}$	340		ns
$t_f$	$di/dt_{on} = 4760\text{ A}/\mu\text{s}$ $di/dt_{off} = 3478\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$	82		ns
$E_{off}$	$dv/dt = 3200\text{ V}/\mu\text{s}$	$T_j = 150^\circ\text{C}$	15.6		mJ
$R_{th(j-c)}$	per IGBT			0.16	$\text{K/W}$
$R_{th(c-s)}$	per IGBT , P12 (reference)		0.051		$\text{K/W}$
$R_{th(c-s)}$	per IGBT , HP-PCM		0.031		$\text{K/W}$



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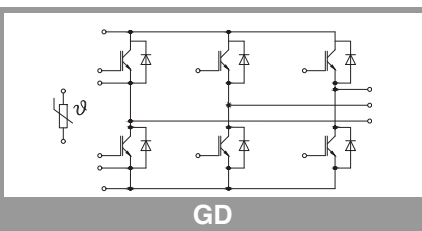
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>Inverse diode</b>						
$V_F = V_{EC}$	$I_F = 300\text{ A}$ $V_{GE} = 0\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$		1.40	1.76	V
		$T_j = 150^\circ\text{C}$		1.39		V
$V_{F0}$	chipelevel	$T_j = 25^\circ\text{C}$		1.04	1.24	V
		$T_j = 150^\circ\text{C}$		0.85		V
$r_F$	chipelevel	$T_j = 25^\circ\text{C}$		1.19	1.76	m $\Omega$
		$T_j = 150^\circ\text{C}$		1.79		m $\Omega$
$I_{RRM}$	$I_F = 300\text{ A}$	$T_j = 150^\circ\text{C}$		212		A
$Q_{rr}$	$di/dt_{off} = 4760\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		21.6		$\mu\text{C}$
$E_{rr}$	$V_{GE} = -15\text{ V}$ $V_{CC} = 300\text{ V}$	$T_j = 150^\circ\text{C}$		5.25		mJ
$R_{th(j-c)}$	per diode				0.25	K/W
$R_{th(c-s)}$	per diode , P12 (reference)			0.047		K/W
$R_{th(c-s)}$	per diode , HP-PCM			0.037		K/W
<b>Module</b>						
$L_{CE}$				20		nH
$R_{CC+EE}$	measured per switch	$T_C = 25^\circ\text{C}$		1.2		m $\Omega$
		$T_C = 125^\circ\text{C}$		1.65		m $\Omega$
$R_{th(c-s)1}$	calculated without thermal coupling			0.004		K/W
$R_{th(c-s)2}$	including thermal coupling, $T_s$ underneath module, P12 (reference)			0.0069		K/W
$R_{th(c-s)2}$	including thermal coupling, $T_s$ underneath module, HP-PCM			0.005		K/W
$M_s$	to heat sink (M5)		3		6	Nm
$M_t$		to terminals (M6)	3		6	Nm
				-		Nm
$w$				398		g
<b>Temperature Sensor</b>						
$R_{100}$	$T_C=100^\circ\text{C}$ ( $R_{25}=5\text{ k}\Omega$ )			$493 \pm 5\%$		$\Omega$
$B_{100/125}$	$R_{(T)}=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$ ; $T[\text{K}]$ ;			$3550 \pm 2\%$		K

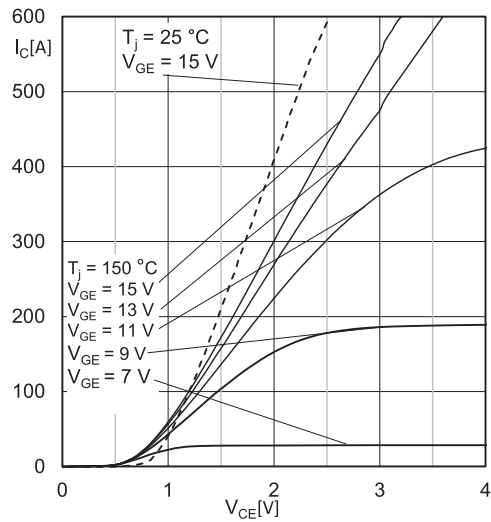


Fig. 1: Typ. output characteristic, inclusive R<sub>CC'+EE'</sub>

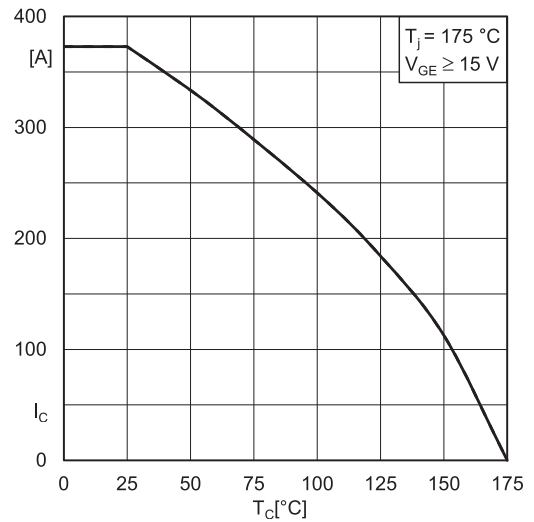


Fig. 2: Rated current vs. temperature I<sub>C</sub> = f(T<sub>C</sub>)

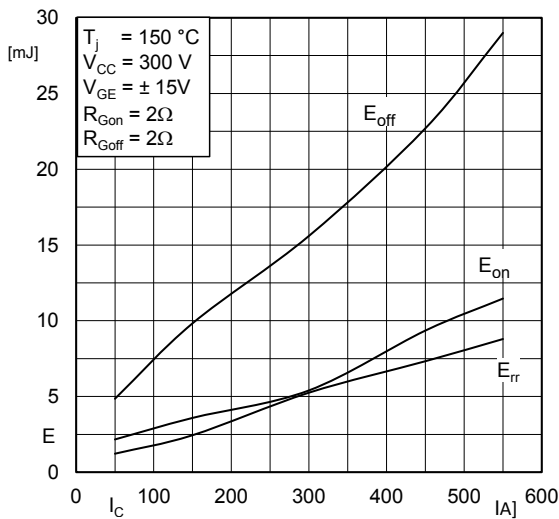


Fig. 3: Typ. turn-on /-off energy = f(I<sub>C</sub>)

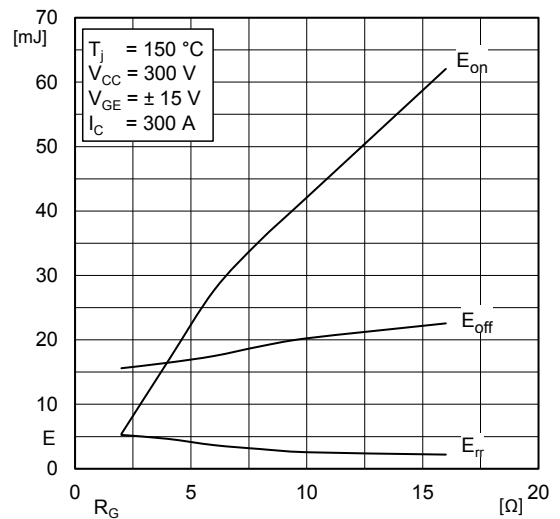


Fig. 4: Typ. turn-on /-off energy = f(R<sub>G</sub>)

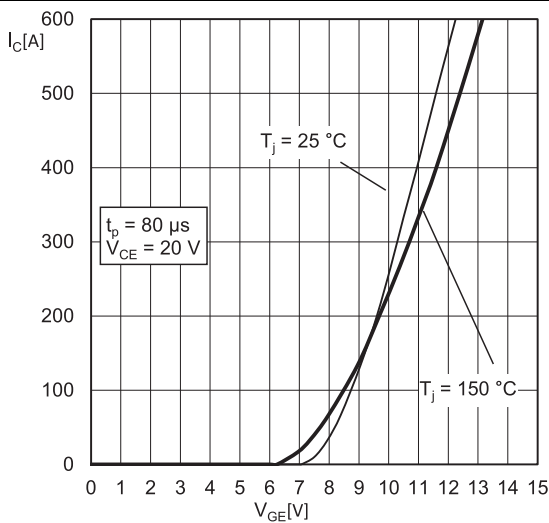


Fig. 5: Typ. transfer characteristic

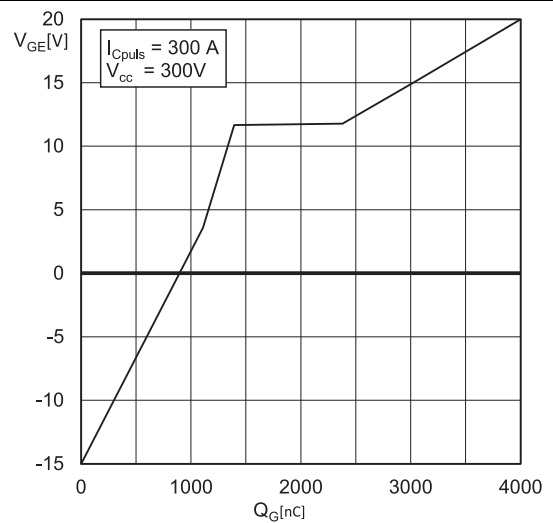


Fig. 6: Typ. gate charge characteristic

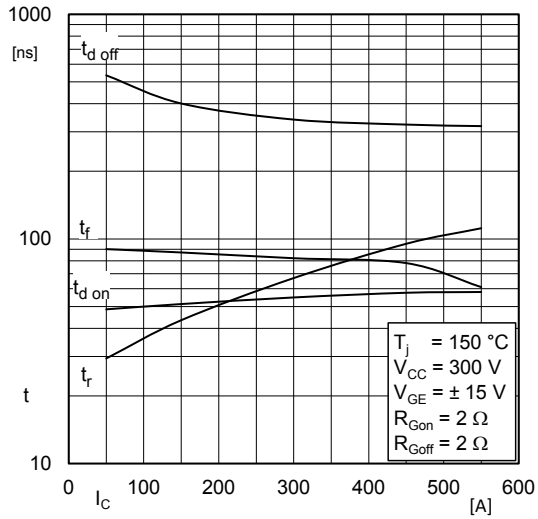


Fig. 7: Typ. switching times vs.  $I_C$

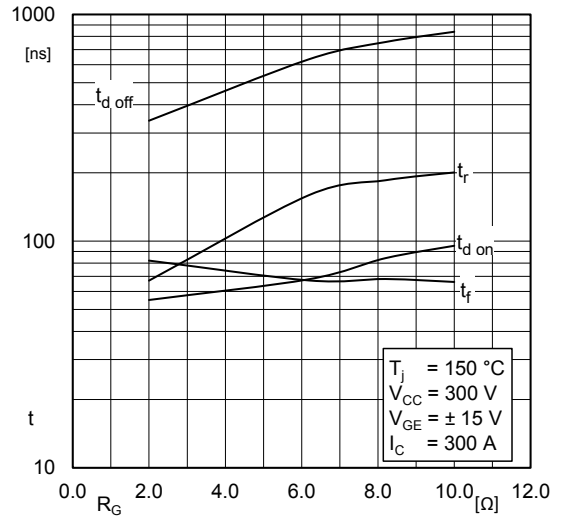


Fig. 8: Typ. switching times vs. gate resistor  $R_G$

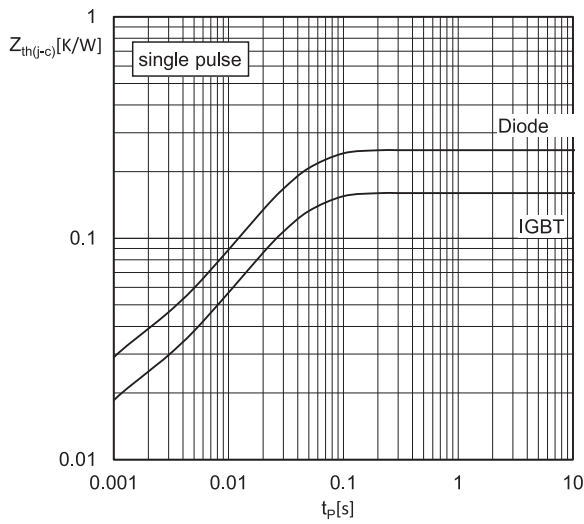


Fig. 9: Transient thermal impedance

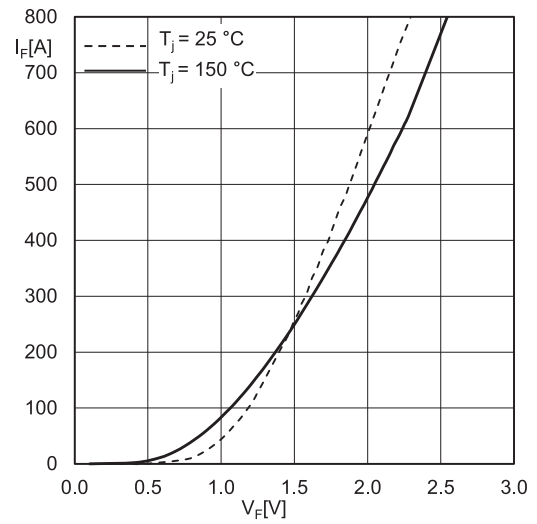


Fig. 10: Typ. CAL diode forward charact., incl.  $R_{CC+EE}$



## IMPORTANT INFORMATION AND WARNINGS

This is an electrostatic discharge sensitive device (ESDS) according to international standard IEC 61340.

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